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| Notice of References Cited | | | Application/Control No. | Applicant(s)/Patent Under Reexamination DEANE, STEVEN C | |
| | | | Examiner Robert R. Rainey | Art Unit 2629 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-6,424,330 | 07-2002 | Johnson, Mark T. | 345/96 |
| * | B | US-7,209,102 | 04-2007 | Moon, Seung Hwan | 345/87 |
| * | C | US-6,771,027 | 08-2004 | Hansen, Ronald L. | 315/169.1 |
| * | D | US-6,229,510 | 05-2001 | Kim et al. | 345/87 |
| * | E | US-5,428,370 | 06-1995 | Knapp et al. | 345/205 |
| * | F | US-5,841,411 | 11-1998 | Francis, Andrew M. | 345/58 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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